

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of claims:

Claim 1 (currently amended): An apparatus for automated testing, calibration and characterization of test adapters for semiconductor devices, comprising:

a holder for holding a test adapter;

at least one probe head adjustably disposed relative to said holder, said probe head having at least two contact pins for testing said test adapter, with said contact pins having an adjustable spacing distance therebetween; and

an adjustment device configured to adjust said probe head relative to said holder.

Claim 2 (original): The apparatus according to claim 1, wherein said at least one probe head is one of a plurality of probe heads.

Claim 3 (original): The apparatus according to claim 1, wherein said probe head is movably disposed in elevation perpendicularly to a surface of said holder.

Claim 4 (original): The apparatus according to claim 1, wherein said adjustment device is a robot arm and said probe head is mounted on said robot arm.

Claim 5 (original): The apparatus according to claim 1, which comprises a control device connected to control a position of said probe head and a rotation of said holder.

Claim 6 (original): The apparatus according to claim 1, wherein said holder is configured to hold test adapters with different diameters.

Claim 7 (original): The apparatus according to claim 1, which comprises a stepping motor disposed to selectively move said holder.

Claim 8 (original): The apparatus according to claim 1, which comprises a control device connected for controlling a distance between said contact pins.

Claim 9 (original): The apparatus according to claim 7, which comprises a control device connected to said stepping motor and wherein said stepping motor is controlled by said control device.

Claim 10 (original): The apparatus according to claim 1, wherein the test adapter is a test card.

Claim 11 (original): The apparatus according to claim 1, wherein the test adapter is formed with a number of contact surfaces one behind the other in a radial direction of the test adapter, and said probe head has a number of said contact pins corresponding to the number of contact surfaces on the test adapter.

Claim 12 (original): The apparatus according to claim 1, wherein said contact pins are formed with pointed ends.

Claim 13 (withdrawn): The apparatus according to claim 1, wherein said contact pins are formed with flat ends, configured to enable contact to be made with contact needles on the test adapter.

Claim 14 (original): The apparatus according to claim 1, wherein said contact pins are spring-biased contact pins.

Claim 15 (previously presented): The apparatus according to claim 14, wherein said contact pins have a profile defining the spring-biased configuration thereof.

Claim 16 (original): The apparatus according to claim 14, wherein said contact pins have a separate spring.

Claim 17 (original): The apparatus according to claim 1, wherein said holder is configured to be rotatable or movable with respect to said adjustment device.

Claim 18 (original): The apparatus according to claim 1, wherein said probe head is adjustable within a coordinate system selected from the group consisting of a polar coordinate system and a cartesian coordinate system.

Claim 19 (previously presented): The apparatus according to claim 1, which comprises an interface board disposed relative to said holder and opposite to said probe head, said interface board having contact pins configured to contact contact surfaces on the test adapter.

Claim 20 (new): An apparatus for automated testing, calibration and characterization of test adapters for semiconductor devices, comprising:

a holder for holding a test adapter, said test adapter having contact surfaces and contact needles opposite said contact surfaces;

at least one probe head adjustably disposed relative to said holder, said probe head having at least two contact pins with an adjustable spacing distance therebetween, said contact pins being adapted to be brought in contact with said contact needles of said test adapter for testing said test adapter;

an adjustment device configured to adjust said probe head relative to said holder; and

an interface board disposed relative to said holder and opposite to said probe head, said interface board having contact pins configured to contact said contact surfaces on said test adapter.